RERMCD1413 reliability plan for PCN 9788

Reliability Evaluation Plan

May 04th, 2016

MMS MCD Quality & Reliability Department-ST Rousset



RERMCD 1413 STM32L04x 32K RELIABILITY TRIALS 2

Qualification plan for new cuts of the dice described in the document

Target: Robustness improvement Assessment in case of Electrical overstress above 4.0V Vdd Absolute maximum rating.

Trial	Test1	Method	Conditions	Sample x lot
				425 Rev Y (Cut 2.2)
DIE	LU	JESD78	125°C	6 x 1
	ESD HBM	ANSI/ESDA/ JEDEC JS-001	1500Ω , 100pF, 25°C 1KV	3 x 1
	ESD CDM	ANSI/ESD STM5.3.1	25°C 500V	3 x 1 in one package
	HTOL	MIL-STD-883 Method 1005 JESD22-A108	125°C , 4.4V 168h	77 x 1

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Public Products List

PCN Title : STM32L04x 32K products - minor revision

PCN Reference : MDG/16/9788

PCN Created on : 03-May-2016

Subject : Public Products List

Dear Customer,

Please find below the Standard Public Products List impacted by the change.

STM32L031G6U6TR	STM32L041K6U6	STM32L041F6P7
STM32L031K6T6	STM32L031G6U7	STM32L031F6P6
STM32L031K6U7	STM32L041C6T7	STM32L031E6Y6TR
STM32L031E6Y6DTR	STM32L031G6U6	STM32L031K6T7
STM32L041K6U7	STM32L031C6T7	STM32L041G6U7
STM32L031F4P3	STM32L041K6U6D	STM32L031K6U6TR
STM32L031F6P7	STM32L041K6T7	STM32L031E4Y6TR
STM32L041K6U6TR	STM32L031F4P6	STM32L031C4T6
STM32L031G4U6	STM32L031K4U6TR	STM32L031K4U6

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